

OptiMOS[™]-5 Power-Transistor





Product Summary

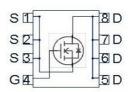
V_{DS}	40	V
$R_{\mathrm{DS(on),max}}$	5.4	$m\Omega$
I _D	40	Α

Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Normal Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

PG-TSDSON-8-32





Туре	Package	Marking
IPZ40N04S5-5R4	PG-TSDSON-8-32	5N0454

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	I _D	T _C =25°C, V _{GS} =10V	40	Α
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 ${\rm V}^{2)}$	40	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25°C	160	
Avalanche energy, single pulse ²⁾	E _{AS}	I _D =20A	53	mJ
Avalanche current, single pulse	I _{AS}	-	40	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T _C =25°C	48	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	3.1	K/W
Thermal resistance, junction - ambient	R_{thJA}	6 cm ² cooling area ³⁾	-	-	60	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0V, $I_{\rm D}$ = 1mA	40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=17\mu{\rm A}$	2.2	2.8	3.4	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	-	-	1	μΑ
		$V_{\rm DS}$ =40V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =7V, I _D =20A	-	5.3	6.3	mΩ
		V _{GS} =10V, I _D =20A	-	4.4	5.4	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	980	1300	pF
Output capacitance	Coss	V_{GS} =0V, V_{DS} =25V, f=1MHz	-	275	366	
Reverse transfer capacitance	C _{rss}		-	19	29	
Turn-on delay time	$t_{d(on)}$		-	4	-	ns
Rise time	t _r	V _{DD} =20V, V _{GS} =10V,	-	2	-	1
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =40A, $R_{\rm G}$ =3.5 Ω	-	6	-	
Fall time	t _f		-	4	-	1
Gate Charge Characteristics ²⁾	_					1
Gate to source charge	Q _{gs}		-	4.6	6.1	nC
Gate to drain charge	Q _{gd}	V _{DD} =32V, I _D =40A,	-	4.1	6.1	
Gate charge total	Qg	$V_{\rm GS}$ =0 to 10V	-	17	23	
Gate plateau voltage	$V_{ m plateau}$		-	4.7	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T _C =25°C	-	-	40	А
Diode pulse current ¹⁾	I _{S,pulse}	7 _C -23 C	-	-	160	
Diode forward voltage	V_{SD}	V _{GS} =0V, I _F =20A, T _j =25°C	-	0.8	1.1	V
Reverse recovery time ¹⁾	t _{rr}	V_R =20V, I_F =40A, di_F/dt =100A/ μ s	-	30	-	ns
Reverse recovery charge ¹⁾	Q _{rr}		-	20	-	nC

 $^{^{1)}}$ Current is limited by package; with an $R_{\rm thJC}$ = 3.1K/W the chip is able to carry 66A at 25°C.

²⁾ The parameter is not subject to production test- verified by design/characterization.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



1 Power dissipation

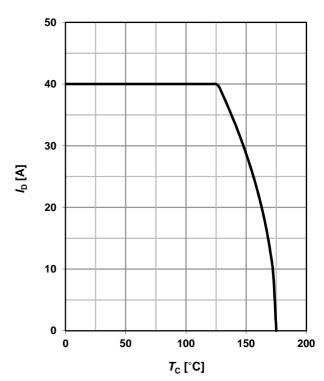
$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} = 10 \text{ V}$$

30 30 20 10 0 0 50 100 150 200

*T*_C [°C]

2 Drain current

$$I_{\rm D} = f(T_{\rm C}); \ V_{\rm GS} = 10 \ {\rm V}$$



3 Safe operating area

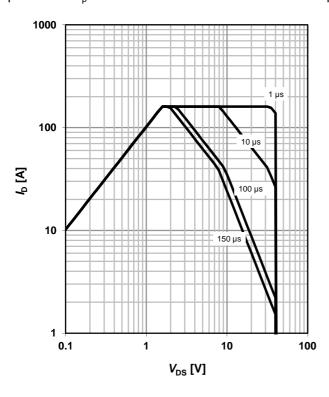
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

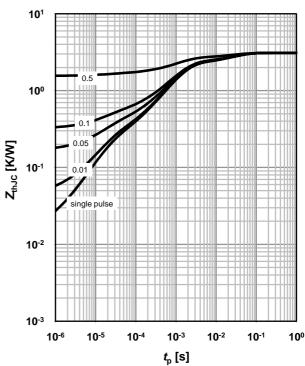
parameter: t_p

4 Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$

parameter: $D=t_p/T$







5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

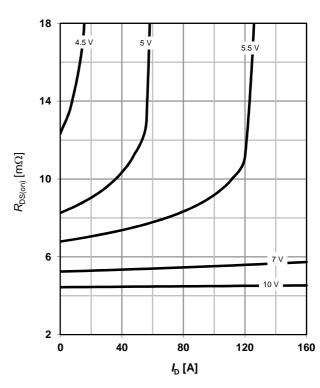
parameter: $V_{\rm GS}$

120 120 40 40 0 1 2 3 V_{DS} [V]

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

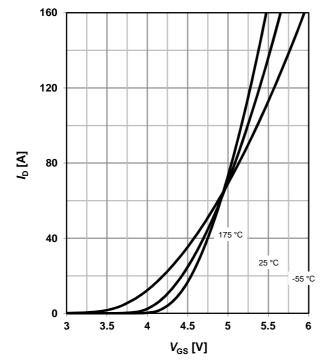
parameter: V_{GS}



7 Typ. transfer characteristics

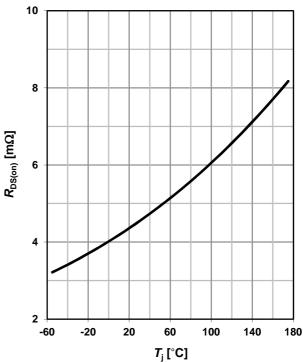
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 20 \text{ A}; V_{GS} = 10 \text{ V}$$





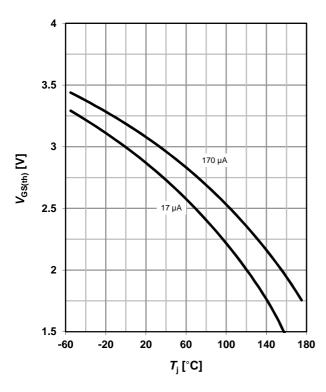
9 Typ. gate threshold voltage

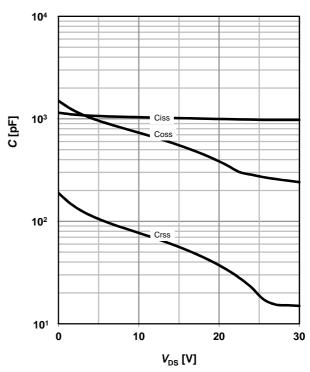
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

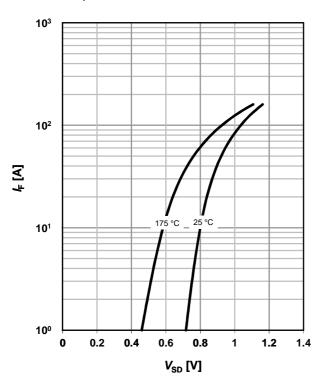
 $IF = f(V_{SD})$

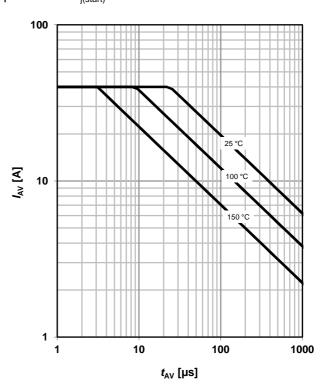
parameter: T_i

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{i(start)}





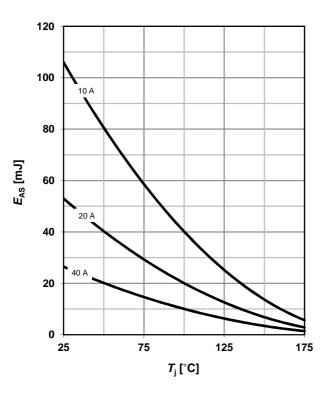


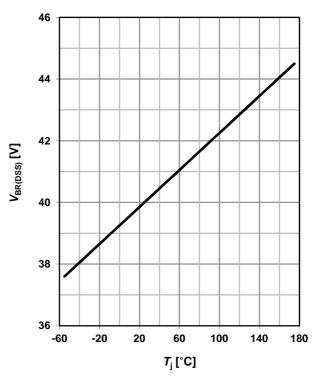
13 Avalanche energy

$E_{AS} = f(T_j)$

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

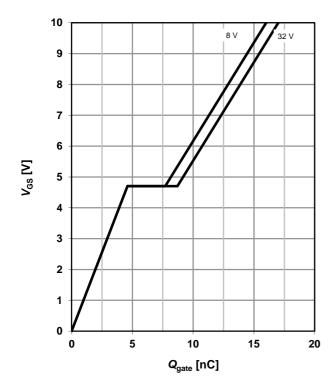




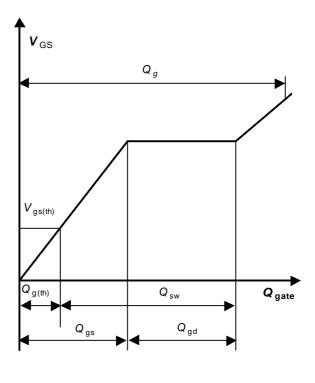
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 40 A pulsed$

parameter: V_{DD}



16 Gate charge waveforms





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Revision History

Version	Date		Changes
Revision 1.0		2015-05-05	Final Data Sheet
Revision 1.1		2015-07-27	Update of package name